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Specification Amendments

Please replace previously amended paragraph [0041] with the following replacement paragraph:

[0041] FIG. 6 thus depicts a configuration that may be utilized to improve column and/or row repairing efficiency in non-volatile memory devices, such as, for example, EPROM, EEPROM and Flash memory devices. Column and/or row repairing data may be read from information array 52, which is associated with the non-volatile memory and can form part of main array 50. This repairing data is generally read to volatile latches (e.g., volatile latch array 60) associated with the non-volatile memory. ECC circuit 70 can be enabled during reading of the repairing data for identifying and repairing defective rows and/or columns associated with the non-volatile memory, despite an error in the repairing information caused by a defective column. ECC circuit 70 can thus be enabled ~~thus be enabled~~ during an access of main array 50 (i.e., which is associated with the non-volatile memory) to thereby correct a correctable error if a particular address corresponds to an address of at least one defective row and/or column. This particular address may, for example, comprise a Y-address corresponding to a defective column.

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Please replace paragraph [0044] with the following replacement paragraph:

[0044] Traditionally, each spare column is reserved for repairing one column corresponding to a specific I/O terminal. If there are 16 I/O terminals for a 16-bit data bus, then 16 spare columns would normally be required to support a one-time repair of any possible column out of the 16 columns accessed at one time. To improve repairing efficiency, the columns for two or more I/O terminals can be made to share a single spare column in a more complicated design. In the specific embodiment described above, all columns associated with a set of four I/O terminals share a single set of five spare columns. The (16,11) Hamming code is well known in the are and is described as pg. 64 of "Error control Coding; Fundamentals and Applications," by Shu Lin & Daniel J. Costello, Jr.).

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